

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination YOON ET AL.	
		Examiner Paul L Rodriguez	Art Unit 2125	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0140637	07-2003	Masui et al.	62/127
	B	US-2003/0097204	05-2003	Coogan, James J.	700/276
	C	US-2003/0033392	02-2003	Nakamura et al.	709/221
	D	US-2002/0029096	03-2002	Takai et al.	700/276
	E	US-2001/0003906	06-2001	Roh, Young Hoon	62/231
	F	US-6,782,294	08-2004	Reich et al.	700/19
	G	US-6,731,992	05-2004	Ziegler, Jr., Eldon W.	700/65
	H	US-6,353,853	03-2002	Gravlin, Keith Robert	709/219
	I	US-6,157,943	12-2000	Meyer, Sheri L.	709/203
	J	US-6,061,603	05-2000	Papadopoulos et al.	700/83
	K	US-6,038,486	03-2000	Saitoh et al.	700/96
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	U.S. Patent Application 10/385533
*	V	U.S. Patent Application 10/376239
*	W	U.S. Patent Application 10/702462
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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